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Understanding <u>Embedded - FPGAs (Field</u> <u>Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	2560
Number of I/O	202
Number of Gates	54000
Voltage - Supply	3V ~ 3.6V, 4.75V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 70°C (TA)
Package / Case	240-BFQFP
Supplier Device Package	240-PQFP (32x32)
Purchase URL	https://www.e-xfl.com/product-detail/microsemi/a42mx36-1pq240

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

Figure 51	BG272	45
Figure 52	PG132	53
Figure 53	CQ172	58

Table 1 • Product profile

Device	A40MX02	A40MX04	A42MX09	A42MX16	A42MX24	A42MX36
Maximum Flip-Flops	147	273	516	928	1,410	1,822
Clocks	1	1	2	2	2	6
User I/O (maximum)	57	69	104	140	176	202
PCI	_	-	_	_	Yes	Yes
Boundary Scan Test (BST)	_	_	_	_	Yes	Yes
Packages (by pin count)						
PLCC	44, 68	44, 68, 84	84	84	84	_
PQFP	100	100	100, 144, 160	100, 160, 208	160, 208	208, 240
VQFP	80	80	100	100	_	_
TQFP	_	_	176	176	176	_
CQFP	_	_	_	172	_	208, 256
PBGA	_	_	_	-	_	272
CPGA	_	_	132	_	_	_

2.6 Temperature Grade Offerings

Table 4 • Temperature Grade Offerings

Package	A40MX02	A40MX04	A42MX09	A42MX16	A42MX24	A42MX36
PLCC 44	C, I, M	C, I, M				
PLCC 68	C, I, A, M	C, I, M				
PLCC 84		C, I, A, M	C, I, A, M	C, I, M	C, I, M	
PQFP 100	C, I, A, M	C, I, A, M	C, I, A, M	C, I, M		
PQFP 144			С			
PQFP 160			C, I, A, M	C, I, M	C, I, A, M	
PQFP 208				C, I, A, M	C, I, A, M	C, I, A, M
PQFP 240						C, I, A, M
VQFP 80	C, I, A, M	C, I, A, M				
VQFP 100			C, I, A, M	C, I, A, M		
TQFP 176			C, I, A, M	C, I, A, M	C, I, A, M	
PBGA 272						C, I, M
CQFP 172				С, М, В		
CQFP 208						С, М, В
CQFP 256						С, М, В
CPGA 132			C, M, B			

Note: C = Commercial

- I = Industrial
 - A = Automotive
 - M = Military

B = MIL-STD-883 Class B

2.7 Speed Grade Offerings

Table 5 •Speed Grade Offerings

	– F	Std	-1	-2	-3
С	Р	Р	Р	Р	Р
I		Р	Р	Р	Р
A		Р			
М		Р	Р		
В		Р	Р		

Note: See the 40MX and 42MX Automotive Family FPGAs datasheet for details on automotive-grade MX offerings.

Contact your local Microsemi Sales representative for device availability.

Figure 5 • A42MX24 and A42MX36 D-Module Implementation

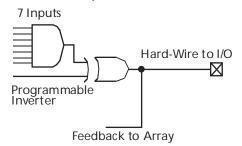
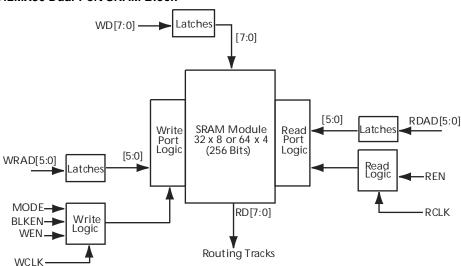


Figure 6 • A42MX36 Dual-Port SRAM Block



3.2.3 Routing Structure

The MX architecture uses vertical and horizontal routing tracks to interconnect the various logic and I/O modules. These routing tracks are metal interconnects that may be continuous or split into segments. Varying segment lengths allow the interconnect of over 90% of design tracks to occur with only two antifuse connections. Segments can be joined together at the ends using antifuses to increase their lengths up to the full length of the track. All interconnects can be accomplished with a maximum of four antifuses.

3.2.3.1 Horizontal Routing

Horizontal routing tracks span the whole row length or are divided into multiple segments and are located in between the rows of modules. Any segment that spans more than one-third of the row length is considered a long horizontal segment. A typical channel is shown in Figure 7, page 10. Within horizontal routing, dedicated routing tracks are used for global clock networks and for power and ground tie-off tracks. Non-dedicated tracks are used for signal nets.

3.2.3.2 Vertical Routing

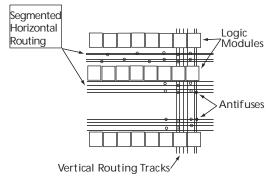
Another set of routing tracks run vertically through the module. There are three types of vertical tracks: input, output, and long. Long tracks span the column length of the module, and can be divided into multiple segments. Each segment in an input track is dedicated to the input of a particular module; each segment in an output track is dedicated to the output of a particular module. Long segments are uncommitted and can be assigned during routing.

Each output segment spans four channels (two above and two below), except near the top and bottom of the array, where edge effects occur. Long vertical tracks contain either one or two segments. An example of vertical routing tracks and segments is shown in Figure 7, page 10.

3.2.3.3 Antifuse Structures

An antifuse is a "normally open" structure. The use of antifuses to implement a programmable logic device results in highly testable structures as well as efficient programming algorithms. There are no pre-existing connections; temporary connections can be made using pass transistors. These temporary connections can isolate individual antifuses to be programmed and individual circuit structures to be tested, which can be done before and after programming. For instance, all metal tracks can be tested for continuity and shorts between adjacent tracks, and the functionality of all logic modules can be verified.

Figure 7 • MX Routing Structure



3.2.4 Clock Networks

The 40MX devices have one global clock distribution network (CLK). A signal can be put on the CLK network by being routed through the CLKBUF buffer.

In 42MX devices, there are two low-skew, high-fanout clock distribution networks, referred to as CLKA and CLKB. Each network has a clock module (CLKMOD) that can select the source of the clock signal from any of the following (Figure 8, page 11):

- Externally from the CLKA pad, using CLKBUF buffer
- Externally from the CLKB pad, using CLKBUF buffer
- Internally from the CLKINTA input, using CLKINT buffer
- Internally from the CLKINTB input, using CLKINT buffer

The clock modules are located in the top row of I/O modules. Clock drivers and a dedicated horizontal clock track are located in each horizontal routing channel.

Clock input pads in both 40MX and 42MX devices can also be used as normal I/Os, bypassing the clock networks.

The A42MX36 device has four additional register control resources, called quadrant clock networks (Figure 9, page 11). Each quadrant clock provides a local, high-fanout resource to the contiguous logic modules within its quadrant of the device. Quadrant clock signals can originate from specific I/O pins or from the internal array and can be used as a secondary register clock, register clear, or output enable.

3.3.7 Low Power Mode

42MX devices have been designed with a Low Power Mode. This feature, activated with setting the special LP pin to HIGH for a period longer than 800 ns, is particularly useful for battery-operated systems where battery life is a primary concern. In this mode, the core of the device is turned off and the device consumes minimal power with low standby current. In addition, all input buffers are turned off, and all outputs and bidirectional buffers are tristated. Since the core of the device is turned off, the states of the registers are lost. The device must be re-initialized when exiting Low Power Mode. I/Os can be driven during LP mode, and clock pins should be driven HIGH or LOW and should not float to avoid drawing current. To exit LP mode, the LP pin must be pulled LOW for over 200 µs to allow for charge pumps to power up, and device initialization will begin.

3.4 **Power Dissipation**

The general power consumption of MX devices is made up of static and dynamic power and can be expressed with the following equation.

3.4.1 General Power Equation

P = [ICCstandby + ICCactive]*VCCI + IOL*VOL*N + IOH*(VCCI - VOH)*M

EQ 1

where:

- ICCstandby is the current flowing when no inputs or outputs are changing.
- ICCactive is the current flowing due to CMOS switching.
- IOL, IOH are TTL sink/source currents.
- VOL, VOH are TTL level output voltages.
- N equals the number of outputs driving TTL loads to VOL.
- M equals the number of outputs driving TTL loads to VOH.

Accurate values for N and M are difficult to determine because they depend on the family type, on design details, and on the system I/O. The power can be divided into two components: static and active.

3.4.2 Static Power Component

The static power due to standby current is typically a small component of the overall power consumption. Standby power is calculated for commercial, worst-case conditions. The static power dissipation by TTL loads depends on the number of outputs driving, and on the DC load current. For instance, a 32-bit bus sinking 4mA at 0.33V will generate 42mW with all outputs driving LOW, and 140mW with all outputs driving HIGH. The actual dissipation will average somewhere in between, as I/Os switch states with time.

3.4.3 Active Power Component

Power dissipation in CMOS devices is usually dominated by the dynamic power dissipation. Dynamic power consumption is frequency-dependent and is a function of the logic and the external I/O. Active power dissipation results from charging internal chip capacitances of the interconnect, unprogrammed antifuses, module inputs, and module outputs, plus external capacitances due to PC board traces and load device inputs. An additional component of the active power dissipation is the totem pole current in the CMOS transistor pairs. The net effect can be associated with an equivalent capacitance that can be combined with frequency and voltage to represent active power dissipation.

The power dissipated by a CMOS circuit can be expressed by the equation:

$$Power(\mu W) = C_{EO}^* VCCA2^* F(1)$$

where:

C_{EQ} = Equivalent capacitance expressed in picofarads (pF)

EQ 2

- VCCA = Power supply in volts (V)
- F = Switching frequency in megahertz (MHz)

3.4.4 Equivalent Capacitance

Equivalent capacitance is calculated by measuring ICCactive at a specified frequency and voltage for each circuit component of interest. Measurements have been made over a range of frequencies at a fixed value of VCC. Equivalent capacitance is frequency-independent, so the results can be used over a wide range of operating conditions. Equivalent capacitance values are shown below.

3.4.5 C_{EQ} Values for Microsemi MX FPGAs

Modules (C_{EQM})3.5

Input Buffers (C_{EQI})6.9

Output Buffers (C_{EQO})18.2

Routed Array Clock Buffer Loads (C_{EQCR})1.4

To calculate the active power dissipated from the complete design, the switching frequency of each part of the logic must be known. The equation below shows a piece-wise linear summation over all components.

Power = VCCA² *[(m×C_{EQM}*f_m)_{modules} + (n*C_{EQI}*f_n)_{inputs} +
$$(p*(C_{EQO}+C_L)*f_p)_{outputs}$$
 + 0.5*(q₁*C_{EQCR}*f_{q1})_{routed_Clk1} + (r_{1*}f_{q1})_{routed_Clk1} + 0.5*(q₂*C_{EQCR}*f_{q2})_{routed_Clk2} + (r_{2*}f_{q2})_{routed_Clk2}(2)]

where:

m = Number of logic modules switching at frequency fm

n = Number of input buffers switching at frequency f_n

p = Number of output buffers switching at frequency f_p

 q_1 = Number of clock loads on the first routed array clock

q₂ = Number of clock loads on the second routed array clock

 r_1 = Fixed capacitance due to first routed array clock

 r_2 = Fixed capacitance due to second routed array clock

C_{EQM} = Equivalent capacitance of logic modules in pF

C_{EQI} = Equivalent capacitance of input buffers in pF

C_{EQO} = Equivalent capacitance of output buffers in pF

C_{EOCR} = Equivalent capacitance of routed array clock in pF

C_L = Output load capacitance in pF

f_m = Average logic module switching rate in MHz

 f_n = Average input buffer switching rate in MHz

 f_p = Average output buffer switching rate in MHz

f_{q1} = Average first routed array clock rate in MHz

EQ 3

Device Type	r1 routed_Clk1	r2 routed_Clk2
A40MX02	41.4	N/A
A40MX04	68.6	N/A
A42MX09	118	118
A42MX16	165	165
A42MX24	185	185
A42MX36	220	220

Fixed Capacitance Values for MX FPGAs (pF)

 f_{a2} = Average second routed array clock rate in MHz)

Table 7 •

3.4.6 Test Circuitry and Silicon Explorer II Probe

MX devices contain probing circuitry that provides built-in access to every node in a design, via the use of Silicon Explorer II. Silicon Explorer II is an integrated hardware and software solution that, in conjunction with the Designer software, allow users to examine any of the internal nets of the device while it is operating in a prototyping or a production system. The user can probe into an MX device without changing the placement and routing of the design and without using any additional resources. Silicon Explorer II's noninvasive method does not alter timing or loading effects, thus shortening the debug cycle and providing a true representation of the device under actual functional situations.

Silicon Explorer II samples data at 100 MHz (asynchronous) or 66 MHz (synchronous). Silicon Explorer II attaches to a PC's standard COM port, turning the PC into a fully functional 18-channel logic analyzer. Silicon Explorer II allows designers to complete the design verification process at their desks and reduces verification time from several hours per cycle to a few seconds.

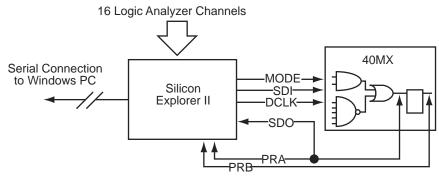
Silicon Explorer II is used to control the MODE, DCLK, SDI and SDO pins in MX devices to select the desired nets for debugging. The user simply assigns the selected internal nets in the Silicon Explorer II software to the PRA/PRB output pins for observation. Probing functionality is activated when the MODE pin is held HIGH.

Figure 12, page 16 illustrates the interconnection between Silicon Explorer II and 40MX devices, while Figure 13, page 17 illustrates the interconnection between Silicon Explorer II and 42MX devices

To allow for probing capabilities, the security fuses must not be programmed. (See User Security, page 12 for the security fuses of 40MX and 42MX devices). Table 8, page 17 summarizes the possible device configurations for probing.

PRA and PRB pins are dual-purpose pins. When the "Reserve Probe Pin" is checked in the Designer software, PRA and PRB pins are reserved as dedicated outputs for probing. If PRA and PRB pins are required as user I/Os to achieve successful layout and "Reserve Probe Pin" is checked, the layout tool will override the option and place user I/Os on PRA and PRB pins.

Figure 12 • Silicon Explorer II Setup with 40MX



3.9.3 Output Drive Characteristics for 3.3 V PCI Signaling

			PCI		MX		
Symbol	Parameter	Condition	Min.	Max.	Min.	Max.	Units
VCCI	Supply Voltage for I/Os		3.0	3.6	3.0	3.6 ²	V
VIH	Input High Voltage		0.5	VCC + 0.5	0.5	VCCI + 0.3	V
VIL	Input Low Voltage		-0.5	0.8	-0.3	0.8	V
IIH	Input High Leakage Current	VIN = 2.7 V		70		10	μA
IIL	Input Leakage Current			-70		-10	μA
VOH	Output High Voltage	IOUT = -2 mA	0.9		3.3		V
VOL	Output Low Voltage	IOUT = 3 mA, 6 mA		0.1		0.1 VCCI	V
C _{IN}	Input Pin Capacitance			10		10	pF
C _{CLK}	CLK Pin Capacitance		5	12		10	pF
L _{PIN}	Pin Inductance			20		< 8 nH ³	nH

Table 25 • DC Specification (3.3 V PCI Signaling)¹

1. PCI Local Bus Specification, Version 2.1, Section 4.2.2.1.

2. Maximum rating for VCCI -0.5 V to 7.0V.

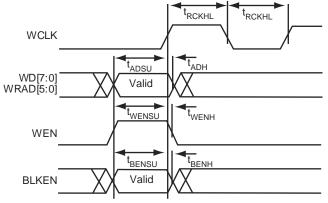
3. Dependent upon the chosen package. PCI recommends QFP and BGA packaging to reduce pin inductance and capacitance.

Table 26 • AC Specifications for (3.3 V PCI Signaling)*

		Condition	PCI	Ν	– Units		
Symbol	Parameter	Condition	Min.	Max.	Min.	Max.	- 011115
ICL	Low Clamp Current	$-5 < VIN \le -1$	-25 + (VIN +1) /0.015		-60	-10	mA
Slew (r)	Output Rise Slew Rate	0.2 V to 0.6 V load	1	4	1.8	2.8	V/ns
Slew (f)	Output Fall Slew Rate	0.6 V to 0.2 V load	1	4	2.8	4.0	V/ns

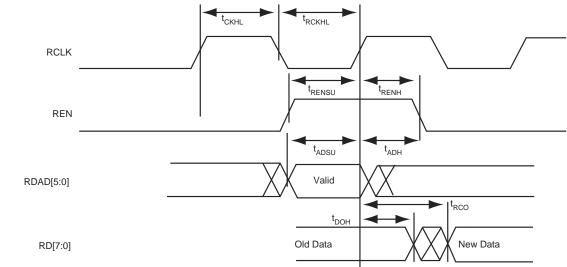
Note: *PCI Local Bus Specification, Version 2.1, Section 4.2.2.2.

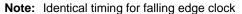
Figure 30 • 42MX SRAM Write Operation



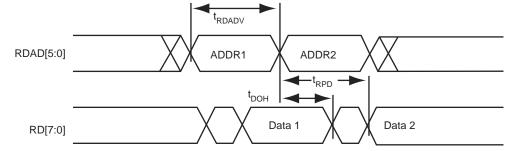
Note: Identical timing for falling edge clock











			–3 Sp	beed	–2 Sp	beed	–1 Sp	beed	Std S	Speed	–F S	peed	
Paramet	ter / Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
t _P	Minimum Period	FO = 16	6.5		7.5		8.5		10.1		14.1		ns
		FO = 128	6.8		7.8		8.9		10.4		14.6		
f _{MAX}	Maximum	FO = 16		113		105		96		83		50	MHz
	Frequency	FO = 128		109		101		92		80		48	
TTL Out	put Module Timing ⁴												
t _{DLH}	Data-to-Pad HIGH			4.7		5.4		6.1		7.2		10.0	ns
t _{DHL}	Data-to-Pad LOW			5.6		6.4		7.3		8.6		12.0	ns
t _{ENZH}	Enable Pad Z to HI	GH		5.2		6.0		6.8		8.1		11.3	ns
t _{ENZL}	Enable Pad Z to LO	WC		6.6		7.6		8.6		10.1		14.1	ns
t _{ENHZ}	Enable Pad HIGH	to Z		11.1		12.8		14.5		17.1		23.9	ns
t _{ENLZ}	Enable Pad LOW to	o Z		8.2		9.5		10.7		12.6		17.7	ns
d _{TLH}	Delta LOW to HIGH	1		0.03		0.03		0.04		0.04		0.06	ns/pF
d _{THL}	Delta HIGH to LOV	V		0.04		0.04		0.05		0.06		0.08	ns/pF

Table 35 •A40MX02 Timing Characteristics (Nominal 3.3 V Operation) (continued)
(Worst-Case Commercial Conditions, VCC = 3.0 V, T_J = 70° C)

		–3 Sp	beed	–2 Sp	beed	–1 Sp	beed	Std S	Speed	–F S	peed	
Parameter / Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
CMOS C	Output Module Timing ⁴											
t _{DLH}	Data-to-Pad HIGH		5.5		6.4		7.2		8.5		11.9	ns
t _{DHL}	Data-to-Pad LOW		4.8		5.5		6.2		7.3		10.2	ns
t _{ENZH}	Enable Pad Z to HIGH		4.7		5.5		6.2		7.3		10.2	ns
t _{ENZL}	Enable Pad Z to LOW		6.8		7.9		8.9		10.5		14.7	ns
t _{ENHZ}	Enable Pad HIGH to Z		11.1		12.8		14.5		17.1		23.9	ns
t _{ENLZ}	Enable Pad LOW to Z		8.2		9.5		10.7		12.6		17.7	ns
d _{TLH}	Delta LOW to HIGH		0.05		0.05		0.06		0.07		0.10	ns/pF
d _{THL}	Delta HIGH to LOW		0.03		0.03		0.04		0.04		0.06	ns/pF

Table 35 •A40MX02 Timing Characteristics (Nominal 3.3 V Operation) (continued)
(Worst-Case Commercial Conditions, VCC = 3.0 V, T_J = 70°C)

1. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.

2. Set-up times assume fanout of 3. Further testing information can be obtained from the Timer utility.

3. The hold time for the DFME1A macro may be greater than 0 ns. Use the Timer tool from the Designer software to check the hold time for this macro

4. Delays based on 35 pF loading

Table 36 •A40MX04 Timing Characteristics (Nominal 5.0 V Operation) (Worst-Case Commercial Conditions,
VCC = 4.75 V, T_J = 70°C)

		–3 S	peed	–2 Sj	beed	–1 S	peed	Std S	Speed	–F S	peed	
Parame	eter / Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Logic N	Iodule Propagation Delays											
t _{PD1}	Single Module		1.2		1.4		1.6		1.9		2.7	ns
t _{PD2}	Dual-Module Macros		2.3		3.1		3.5		4.1		5.7	ns
t _{CO}	Sequential Clock-to-Q		1.2		1.4		1.6		1.9		2.7	ns
t _{GO}	Latch G-to-Q		1.2		1.4		1.6		1.9		2.7	ns
t _{RS}	Flip-Flop (Latch) Reset-to-Q		1.2		1.4		1.6		1.9		2.7	ns
Logic N	Iodule Predicted Routing Dela	ys ¹										
t _{RD1}	FO = 1 Routing Delay		1.2		1.6		1.8		2.1		3.0	ns
t _{RD2}	FO = 2 Routing Delay		1.9		2.2		2.5		2.9		4.1	ns
t _{RD3}	FO = 3 Routing Delay		2.4		2.8		3.2		3.7		5.2	ns
t _{RD4}	FO = 4 Routing Delay		2.9		3.4		3.9		4.5		6.3	ns
t _{RD8}	FO = 8 Routing Delay		5.0		5.8		6.6		7.8		10.9	ns
Logic N	Iodule Sequential Timing ²											
t _{SUD}	Flip-Flop (Latch) Data Input Set-Up	3.1		3.5		4.0		4.7		6.6		ns
t _{HD} ³	Flip-Flop (Latch) Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{SUENA}	Flip-Flop (Latch) Enable Set-Up	3.1		3.5		4.0		4.7		6.6		ns

		–3 Sp	beed	–2 Sp	beed	–1 Sp	beed	Std S	Speed	–F S	peed	
Parameter / Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
t _{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width	4.5		4.9		5.6		6.6		9.2		ns
t _A	Flip-Flop Clock Input Period	3.5		3.8		4.3		5.1		7.1		ns
t _{INH}	Input Buffer Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{INSU}	Input Buffer Latch Set-Up	0.3		0.3		0.4		0.4		0.6		ns
t _{OUTH}	Output Buffer Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{OUTSU}	Output Buffer Latch Set-Up	0.3		0.3		0.4		0.4		0.6		ns
f _{MAX}	Flip-Flop (Latch) Clock Frequenc	у	268		244		224		195		117	MHz

Table 38 • A42MX09 Timing Characteristics (Nominal 5.0 V Operation) (continued) (Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)

			–3 Sp	beed	–2 S	peed	–1 Sp	beed	Std S	Speed	–F S	peed	
Parame	eter / Description		Min.	Max.	Units								
Input M	lodule Propagation Del	ays											
t _{INYH}	Pad-to-Y HIGH			1.0		1.2		1.3		1.6		2.2	ns
t _{INYL}	Pad-to-Y LOW			0.8		0.9		1.0		1.2		1.7	ns
t _{INGH}	G to Y HIGH			1.3		1.4		1.6		1.9		2.7	ns
t _{INGL}	G to Y LOW			1.3		1.4		1.6		1.9		2.7	ns
Input M	lodule Predicted Routi	ng Delays ²											
t _{IRD1}	FO = 1 Routing Delay	,		2.0		2.2		2.5		3.0		4.2	ns
t _{IRD2}	FO = 2 Routing Delay	,		2.3		2.5		2.9		3.4		4.7	ns
t _{IRD3}	FO = 3 Routing Delay	,		2.5		2.8		3.2		3.7		5.2	ns
t _{IRD4}	FO = 4 Routing Delay	,		2.8		3.1		3.5		4.1		5.7	ns
t _{IRD8}	FO = 8 Routing Delay	,		3.7		4.1		4.7		5.5		7.7	ns
Global	Clock Network												
t _{CKH}	Input LOW to HIGH	FO = 32		2.4		2.7		3.0		3.6		5.0	ns
-		FO = 256		2.7		3.0		3.4		4.0		5.5	ns
t _{CKL}	Input HIGH to LOW	FO = 32		3.5		3.9		4.4		5.2		7.3	ns
		FO = 256		3.9		4.3		4.9		5.7		8.0	ns
t _{PWH}	Minimum Pulse Width HIGH	FO = 32 FO = 256	1.2 1.3		1.4 1.5		1.5 1.7		1.8 2.0		2.5 2.7		ns ns
t _{PWL}	Minimum Pulse	FO = 32	1.2		1.4		1.5		1.8		2.5		ns
PVVL	Width LOW	FO = 256	1.3		1.5		1.7		2.0		2.7		ns
t _{CKSW}	Maximum Skew	FO = 32		0.3		0.3		0.4		0.5		0.6	ns
		FO = 256		0.3		0.3		0.4		0.5		0.6	ns
t _{SUEXT}	Input Latch	FO = 32	0.0		0.0		0.0		0.0		0.0		ns
	External Set-Up	FO = 256	0.0		0.0		0.0		0.0		0.0		ns
t_{HEXT}	Input Latch	FO = 32	2.3		2.6		3.0		3.5		4.9		ns
	External Hold	FO = 256	2.2		2.4		3.3		3.9		5.5		ns
t _P	Minimum Period	FO = 32	3.4		3.7		4.0		4.7		7.8		ns
		FO = 256	3.7		4.1		4.5		5.2		8.6		ns
f_{MAX}	Maximum Frequency	FO = 32 FO = 256		296 268		269 244		247 224		215 195		129 117	MHz MHz
		PO = 200		200		244		224		190		117	

Table 38 •A42MX09 Timing Characteristics (Nominal 5.0 V Operation) (continued) (Worst-Case Commercial
Conditions, VCCA = 4.75 V, T_J = 70°C)

			–3 S	peed	–2 S	peed	–1 Sj	beed	Std S	Speed	–F S	peed	
Parame	ter / Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Input M	odule Predicted Routing	g Delays ²											
t _{IRD1}	FO = 1 Routing Delay			2.8		3.1		3.5		4.1		5.7	ns
t _{IRD2}	FO = 2 Routing Delay			3.2		3.5		4.1		4.8		6.7	ns
t _{IRD3}	FO = 3 Routing Delay			3.7		4.1		4.7		5.5		7.7	ns
t _{IRD4}	FO = 4 Routing Delay			4.2		4.6		5.3		6.2		8.7	ns
t _{IRD8}	FO = 8 Routing Delay			6.1		6.8		7.7		9.0		12.6	ns
Global (Clock Network												
t _{CKH}	Input LOW to HIGH	FO = 32 FO = 635		4.6 5.0		5.1 5.6		5.7 6.3		6.7 7.4		9.3 10.3	ns ns
t _{CKL}	Input HIGH to LOW	FO = 32 FO = 635		5.3 6.8		5.9 7.6		6.7 8.6		7.8 10.1		11.0 14.1	ns ns
t _{PWH}	Minimum Pulse Width HIGH	FO = 32 FO = 635	2.5 2.8		2.7 3.1		3.1 3.5		3.6 4.1		5.1 5.7		ns ns
t _{PWL}	Minimum Pulse Width LOW	FO = 32 FO = 635	2.5 2.8		2.7 3.1		3.1 3.5		3.6 4.1		5.1 5.7		ns ns
t _{CKSW}	Maximum Skew	FO = 32 FO = 635		1.0 1.0		1.2 1.2		1.3 1.3		1.5 1.5		2.2 2.2	ns ns
t _{SUEXT}	Input Latch External Set-Up	FO = 32 FO = 635	0.0 0.0		0.0 0.0		0.0 0.0		0.0 0.0		0.0 0.0		ns ns
t _{HEXT}	Input Latch External Hold	FO = 32 FO = 635	4.0 4.6		4.4 5.2		5.0 5.9		5.9 6.9		8.2 9.6		ns ns
t _P	Minimum Period (1/f _{MAX})	FO = 32 FO = 635	9.2 9.9		10.2 11.0		11.1 12.0		12.7 13.8		21.2 23.0		ns ns
f _{MAX}	Maximum Datapath Frequency	FO = 32 FO = 635		108 100		98 91		90 83		79 73		47 44	MHz MHz
TTL Out	tput Module Timing ⁵												
t _{DLH}	Data-to-Pad HIGH			3.6		4.0		4.5		5.3		7.4	ns
t _{DHL}	Data-to-Pad LOW			4.2		4.6		5.2		6.2		8.6	ns
t _{ENZH}	Enable Pad Z to HIGH			3.7		4.2		4.7		5.5		7.7	ns
t _{ENZL}	Enable Pad Z to LOW			4.1		4.6		5.2		6.1		8.5	ns
t _{ENHZ}	Enable Pad HIGH to Z			7.34		8.2		9.3		10.9		15.3	ns
TTL Out	tput Module Timing ⁵												
t _{ENLZ}	Enable Pad LOW to Z			6.9		7.6		8.7		10.2		14.3	ns
t _{GLH}	G-to-Pad HIGH			4.9		5.5		6.2		7.3		10.2	ns
t _{GHL}	G-to-Pad LOW			4.9		5.5		6.2		7.3		10.2	ns
t _{LSU}	I/O Latch Output Set-L	Јр	0.7		0.7		0.8		1.0		1.4		ns
t _{LH}	I/O Latch Output Hold		0.0		0.0		0.0		0.0		0.0		ns
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O			7.9		8.8		10.0		11.8		16.5	ns

Table 45 •A42MX36 Timing Characteristics (Nominal 3.3 V Operation) (continued) (Worst-Case Commercial
Conditions, VCCA = 3.0 V, T_J = 70°C)

		–3 S	peed	–2 S	peed	–1 S	peed	Std S	Speed	–F S	peed	
Parame	eter / Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
t _{ACO}	Array Latch Clock-to-Out (Pad-to-Pad) 32 I/O		10.9		12.1		13.7		16.1		22.5	ns
d _{TLH}	Capacitive Loading, LOW to HIGH		0.10		0.11		0.12		0.14		0.20	ns/pF
d _{THL}	Capacitive Loading, HIGH to LOW		0.10		0.11		0.12		0.14		0.20	ns/pF
CMOS	Output Module Timing ⁵											
t _{DLH}	Data-to-Pad HIGH		4.9		5.5		6.2		7.3		10.3	ns
t _{DHL}	Data-to-Pad LOW		3.4		3.8		4.3		5.1		7.1	ns
t _{ENZH}	Enable Pad Z to HIGH		3.7		4.1		4.7		5.5		7.7	ns
t _{ENZL}	Enable Pad Z to LOW		4.1		4.6		5.2		6.1		8.5	ns
t _{ENHZ}	Enable Pad HIGH to Z		7.4		8.2		9.3		10.9		15.3	ns
t _{ENLZ}	Enable Pad LOW to Z		6.9		7.6		8.7		10.2		14.3	ns
t _{GLH}	G-to-Pad HIGH		7.0		7.8		8.9		10.4		14.6	ns
t _{GHL}	G-to-Pad LOW		7.0		7.8		8.9		10.4		14.6	ns
t _{LSU}	I/O Latch Set-Up	0.7		0.7		0.8		1.0		1.4		ns
t _{LH}	I/O Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O		7.9		8.8		10.0		11.8		16.5	ns

Table 45 • A42MX36 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)

1. For dual-module macros, use $t_{PD1} + t_{RD1} + t_{PDn}$, $t_{CO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.

2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.

3. Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the Timer utility.

4. Set-up and hold timing parameters for the Input Buffer Latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.

5. Delays based on 35 pF loading.

3.12 Pin Descriptions

This section lists the pin descriptions for 40MX and 42MX series FPGAs.

CLK/A/B, I/O Global Clock

Clock inputs for clock distribution networks. CLK is for 40MX while CLKA and CLKB are for 42MX devices. The clock input is buffered prior to clocking the logic modules. This pin can also be used as an I/O.

DCLK, I/ODiagnostic Clock

Clock input for diagnostic probe and device programming. DCLK is active when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

GND, Ground

Input LOW supply voltage.

I/O, Input/Output

Table 50 • PQ 100

PQ100					
Pin Number	A40MX02 Function	A40MX04 Function	A42MX09 Function	A42MX16 Function	
56	VCC	VCC	I/O	I/O	
57	I/O	I/O	GND	GND	
58	I/O	I/O	I/O	I/O	
59	I/O	I/O	I/O	I/O	
60	I/O	I/O	I/O	I/O	
61	I/O	I/O	I/O	I/O	
62	I/O	I/O	I/O	I/O	
63	GND	GND	I/O	I/O	
64	I/O	I/O	LP	LP	
65	I/O	I/O	VCCA	VCCA	
66	I/O	I/O	VCCI	VCCI	
67	I/O	I/O	VCCA	VCCA	
68	I/O	I/O	I/O	I/O	
69	VCC	VCC	I/O	I/O	
70	I/O	I/O	I/O	I/O	
71	I/O	I/O	I/O	I/O	
72	I/O	I/O	GND	GND	
73	I/O	I/O	I/O	I/O	
74	I/O	I/O	I/O	I/O	
75	I/O	I/O	I/O	I/O	
76	I/O	I/O	I/O	I/O	
77	NC	NC	I/O	I/O	
78	NC	NC	I/O	I/O	
79	NC	NC	SDI, I/O	SDI, I/O	
80	NC	I/O	I/O	I/O	
81	NC	I/O	I/O	I/O	
82	NC	I/O	I/O	I/O	
83	I/O	I/O	I/O	I/O	
84	I/O	I/O	GND	GND	
85	I/O	I/O	I/O	I/O	
86	GND	GND	I/O	I/O	
87	GND	GND	PRA, I/O	PRA, I/O	
88	I/O	I/O	I/O	I/O	
89	I/O	I/O	CLKA, I/O	CLKA, I/O	
90	CLK, I/O	CLK, I/O	VCCA	VCCA	
91	I/O	I/O	I/O	I/O	
92	MODE	MODE	CLKB, I/O	CLKB, I/O	

VQ100		
Pin Number	A42MX09 Function	A42MX16 Function
57	I/O	I/O
58	I/O	I/O
59	I/O	I/O
60	I/O	I/O
61	I/O	I/O
62	LP	LP
63	VCCA	VCCA
64	VCCI	VCCI
65	VCCA	VCCA
66	I/O	I/O
67	I/O	I/O
68	I/O	I/O
69	I/O	I/O
70	GND	GND
71	I/O	I/O
72	I/O	I/O
73	I/O	I/O
74	I/O	I/O
75	I/O	I/O
76	I/O	I/O
77	SDI, I/O	SDI, I/O
78	I/O	I/O
79	I/O	I/O
80	I/O	I/O
81	I/O	I/O
82	GND	GND
83	I/O	I/O
84	I/O	I/O
85	PRA, I/O	PRA, I/O
86	I/O	I/O
87	CLKA, I/O	CLKA, I/O
88	VCCA	VCCA
89	I/O	I/O
90	CLKB, I/O	CLKB, I/O
91	I/O	I/O
92	PRB, I/O	PRB, I/O

Table 57 • TQ176

TQ176			
Pin Number	A42MX09 Function	A42MX16 Function	A42MX24 Function
10	NC	I/O	I/O
11	NC	I/O	I/O
12	I/O	I/O	I/O
13	NC	VCCA	VCCA
14	I/O	I/O	I/O
15	I/O	I/O	I/O
16	I/O	I/O	I/O
17	I/O	I/O	I/O
18	GND	GND	GND
19	NC	I/O	I/O
20	NC	I/O	I/O
21	I/O	I/O	I/O
22	NC	I/O	I/O
23	GND	GND	GND
24	NC	VCCI	VCCI
25	VCCA	VCCA	VCCA
26	NC	I/O	I/O
27	NC	I/O	I/O
28	VCCI	VCCA	VCCA
29	NC	I/O	I/O
30	I/O	I/O	I/O
31	I/O	I/O	I/O
32	I/O	I/O	I/O
33	NC	NC	I/O
34	I/O	I/O	I/O
35	I/O	I/O	I/O
36	I/O	I/O	I/O
37	NC	I/O	I/O
38	NC	NC	I/O
39	I/O	I/O	I/O
40	I/O	I/O	I/O
11	I/O	I/O	I/O
12	I/O	I/O	I/O
43	I/O	I/O	I/O
44	I/O	I/O	I/O
45	GND	GND	GND
46	I/O	I/O	TMS, I/O

Table 60 •	BG272
BG272	
Pin Numbe	r A42MX36 Function
J9	GND
J10	GND
J11	GND
J12	GND
J17	VCCA
J18	I/O
J19	I/O
J20	I/O
K1	I/O
K2	I/O
K3	I/O
K4	VCCI
K9	GND
K10	GND
K11	GND
K12	GND
K17	I/O
K18	VCCA
K19	VCCA
K20	LP
L1	I/O
L2	I/O
L3	VCCA
L4	VCCA
L9	GND
L10	GND
L11	GND
L12	GND
L17	VCCI
L18	I/O
L19	I/O
L20	TCK, I/O
M1	I/O
M2	I/O
M3	I/O
M4	VCCI
M9	GND